## **VBED1606**



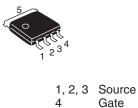
# N-Channel 60 V (D-S) 175 °C MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	60			
$R_{DS(on)} (\Omega)$ at $V_{GS} = 10 V$	0.0050			
$R_{DS(on)}(\Omega)$ at $V_{GS} = 4.5 V$	0.0055			
I <sub>D</sub> (A)	97			
Configuration	Single			

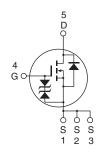
#### **FEATURES**

- Trench Power MOSFET
- Package with Low Thermal Resistance
- 100 %  $\rm R_g$  and UIS Tested





Gate 5 Drain



<b>ABSOLUTE MAXIMUM RATINGS</b> ( $T_C = 25 \text{ °C}$ , unless otherwise noted)					
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V <sub>DS</sub>	60	V	
Gate-Source Voltage		V <sub>GS</sub> ± 20		v	
Continuous Drain Current	T <sub>C</sub> = 25 °C	1	97		
	T <sub>C</sub> = 125 °C	I <sub>D</sub>	56		
Continuous Source Current (Diode Conduction) <sup>a</sup>		I <sub>S</sub>	100	А	
Pulsed Drain Current <sup>b</sup>		I <sub>DM</sub>	290		
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	45		
Single Pulse Avalanche Energy		E <sub>AS</sub>	101	mJ	
Maximum Power Dissipation <sup>b</sup>	T <sub>C</sub> = 25 °C	D	136	W	
	T <sub>C</sub> = 125 °C	P <sub>D</sub>	45	~~~	
Operating Junction and Storage Temperature Range	ge	T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C	

THERMAL RESISTANCE RATINGS					
PARAMETER		SYMBOL	LIMIT	UNIT	
Junction-to-Ambient	PCB Mount <sup>c</sup>	R <sub>thJA</sub>	50	°C/W	
Junction-to-Case (Drain)		R <sub>thJC</sub>	1.1	C/W	

#### Notes

- a. Package limited.
- b. Pulse test; pulse width  $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- c. When mounted on 1" square PCB (FR-4 material).
- d. Parametric verification ongoing.

SPECIFICATIONS ( $T_C = 25 \ ^{\circ}C_{,}$	, unless otherv	vise noted)					
PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static	•	•					
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 V, I_D = 250 \mu A$		60	-	I	v
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$		2.0	2.5	
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>DS</sub> =	$V_{DS} = 0 V, V_{GS} = \pm 20 V$		-	± 100	nA
Zero Gate Voltage Drain Current		$V_{GS} = 0 V$	V <sub>DS</sub> = 60 V	-	-	1	μΑ
	I <sub>DSS</sub>	$V_{GS} = 0 V$	$V_{DS} = 60 \text{ V}, \text{ T}_{J} = 125 ^{\circ}\text{C}$	-	-	50	
		$V_{GS} = 0 V$	$V_{DS} = 60 \text{ V}, \text{ T}_{J} = 175 ^{\circ}\text{C}$	-	-	150	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{GS} = 10 V$	$V_{DS} \ge 5 V$	50	-	-	Α
Drain-Source On-State Resistance <sup>a</sup>		$V_{GS} = 10 V$	I <sub>D</sub> = 25 A	-	0.0050	-	Ω
	В	$V_{GS} = 10 V$	I <sub>D</sub> = 25 A, T <sub>J</sub> = 125 °C	-	0.0117	-	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 V$	I <sub>D</sub> = 25 A, T <sub>J</sub> = 175 °C	-	0.0149	-	
		$V_{GS} = 4.5 V$	I <sub>D</sub> = 20 A	-	0.0055	-	
Forward Transconductanceb	g <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 25 A		-	177	-	S
Dynamic <sup>b</sup>	·						
Input Capacitance	C <sub>iss</sub>		V <sub>DS</sub> = 25 V, f = 1 MHz	-	4844	6060	pF
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V		-	441	555	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	200	250	
Total Gate Charge <sup>c</sup>	Qg		$V_{DS}$ = 30 V, I <sub>D</sub> = 50 A	-	82	125	nC
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		-	14.5	-	
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>			-	13.5	-	
Gate Resistance	Rg	f = 1 MHz		1	2	3	Ω
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>				14	21	ns
Rise Time <sup>c</sup>	t <sub>r</sub>	$\begin{array}{l} V_{\text{DD}}=30 \text{ V}, \ R_{\text{L}}=0.6 \ \Omega\\ I_{\text{D}}\cong 50 \text{ A}, \ V_{\text{GEN}}=10 \text{ V}, \ R_{g}=1 \ \Omega \end{array}$		-	5	8	
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>			-	41	62	
Fall Time <sup>c</sup>	t <sub>f</sub>			-	7	11	
Source-Drain Diode Ratings and Char	acteristics <sup>b</sup>	·			·		
Pulsed Current <sup>a</sup>	I <sub>SM</sub>			-	-	290	Α
Forward Voltage	V <sub>SD</sub>	$I_F = 50 \text{ A}, V_{GS} = 0 \text{ V}$		-	0.9	1.5	V

Notes

a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

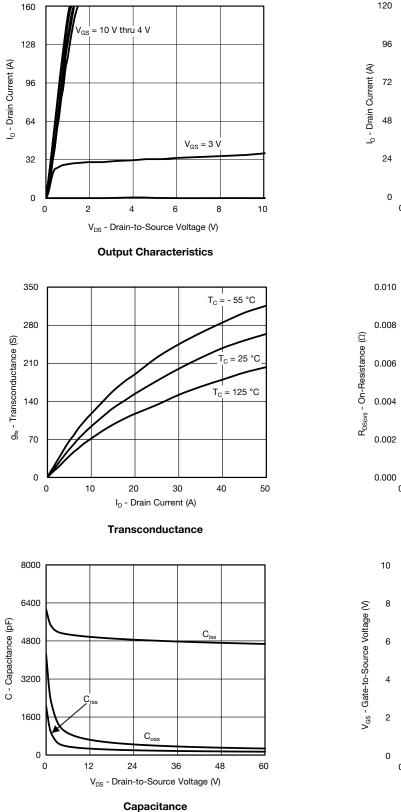
c. Independent of operating temperature.

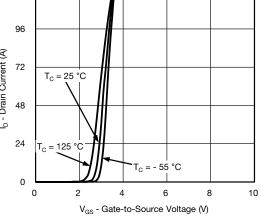
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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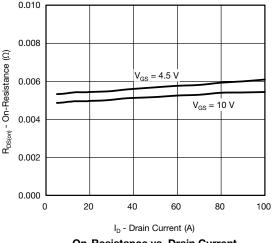
## **TYPICAL CHARACTERISTICS** ( $T_A = 25 \text{ °C}$ , unless otherwise noted)



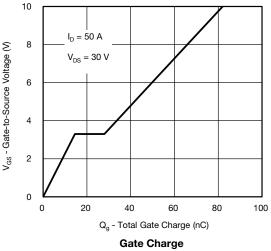


120

**Transfer Characteristics** 

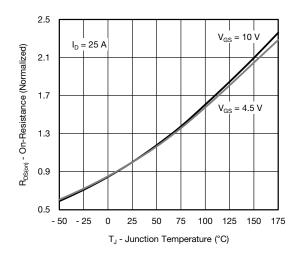


**On-Resistance vs. Drain Current** 

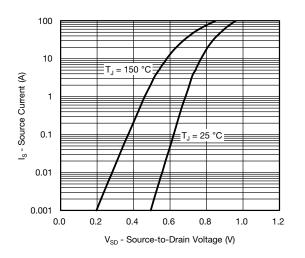




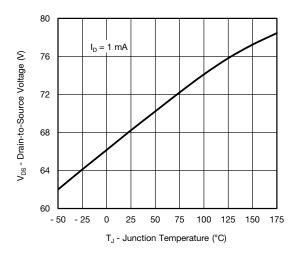
## **TYPICAL CHARACTERISTICS** ( $T_A = 25 \text{ °C}$ , unless otherwise noted)



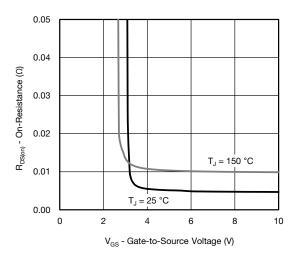
**On-Resistance vs. Junction Temperature** 



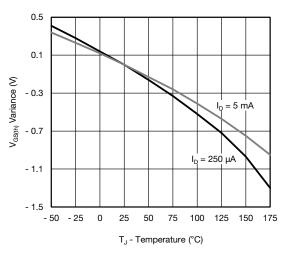
Source Drain Diode Forward Voltage



Drain Source Breakdown vs. Junction Temperature



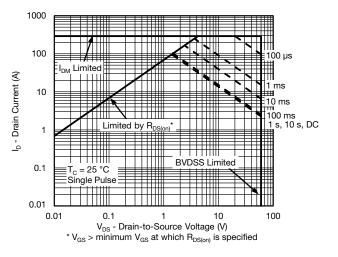
**On-Resistance vs. Gate-to-Source Voltage** 



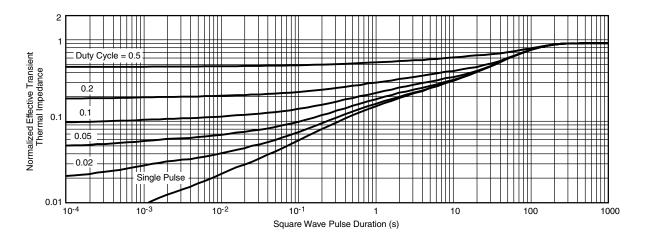
**Threshold Voltage** 



#### **THERMAL RATINGS** ( $T_A = 25 \text{ °C}$ , unless otherwise noted)



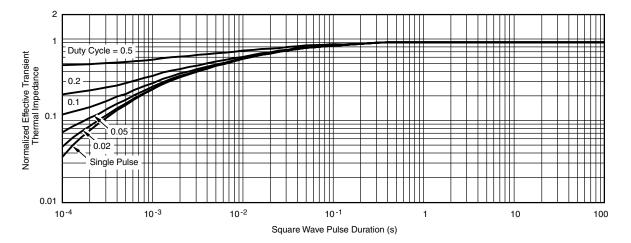
Safe Operating Area



Normalized Thermal Transient Impedance, Junction-to-Ambient



#### **THERMAL RATINGS** ( $T_A = 25 \text{ °C}$ , unless otherwise noted)



#### Normalized Thermal Transient Impedance, Junction-to-Case

#### Note

The characteristics shown in the two graphs

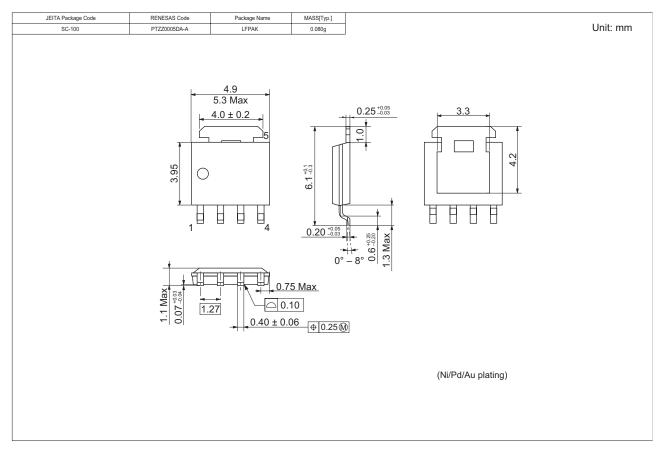
- Normalized Transient Thermal Impedance Junction-to-Ambient (25 °C)

- Normalized Transient Thermal Impedance Junction-to-Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.



## **Package Dimensions**





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